

Product description

Platinum Silicide Probes Contact Mode

NANOSENSORS™ PtSi-CONT are designed for contact mode (repulsive mode) AFM imaging. Furthermore this AFM probe can be used for force-distance spectroscopy or pulsed force mode (PFM). The CONT type is optimized for high sensitivity due a low force constant.

For applications that require a wear resistant and electrically conductive AFM tip we recommend this type. **NANOSENSORS™ PtSi-CONT** are suitable for C-AFM, Tunneling AFM (TUNA) and Scanning Capacitance Microscopy (SCM).

The AFM probe offers unique features:

- platinum silicide coating with excellent conductivity and good wear-out behaviour
- chemically inert
- high mechanical Q-factor for high sensitivity
- alignment grooves on backside of the holder chip
- compatible with [PointProbe® Plus XY-Alignment Series](#)

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	13	6 - 21
Force Constant [N/m]	0.2	0.02 - 0.77
Length [µm]	450	440 - 460
Mean Width [µm]	50	42.5 - 57.5
Thickness [µm]	2	1 - 3

Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PtSi-CONT-10	10	of all probes
PtSi-CONT-20	20	of all probes
PtSi-CONT-50	50